

700V 210mΩ SolidGaN with Gate Clamp and DESAT

1. Features

- Latest High-Voltage G3.0 GaN Technology
- 210mΩ E-Mode GaN with Built-In Gate Clamp
- 700V Continuous, 750V Pulsed Voltage Rating
- Wide 8V to 20V Gate Input Voltage Range
- Self-Powered Technology, No Peripheral Power Required
- Adjustable Turn-On Slew Rate by External Gate Resistors
- Zero Reverse Recovery Charge
- Ultra-High Switching Frequency
- Suitable for Conventional PWM Controllers
- Available in 3-Lead TO-252 Package

2. Applications

- Boost PFC, QR Flyback Topology
- AHB, LLC Topology
- AC-DC Power Adaptor, LED Lighting
- TV Power, Home Appliance Power

3. Description

The ISG6134A SolidGaN IC seamlessly integrates a 700V enhanced mode Gallium Nitride (GaN) FET with a built-in gate clamp and DESAT protection in a conventional TO-252 package, establishing a new standard for performance, ease of use, and reliability in power electronics. It provides self-powered features without requiring a sustainable supply voltage for internal supply, ensuring consistent driving of GaN FET. With built-in DESAT protection, the ISG6134A further ensures device robustness and system safety.

The ISG6134A offers the ability to adjust the turn-on slew rate of the GaN FET using external gate resistors, allowing users to optimize efficiency and EMI performance. The ISG6134A's high integration level with a GaN FET and robust protection makes it suitable for a range of applications, from simple setups with low component counts to high-frequency and high-power applications.

4. Typical Application

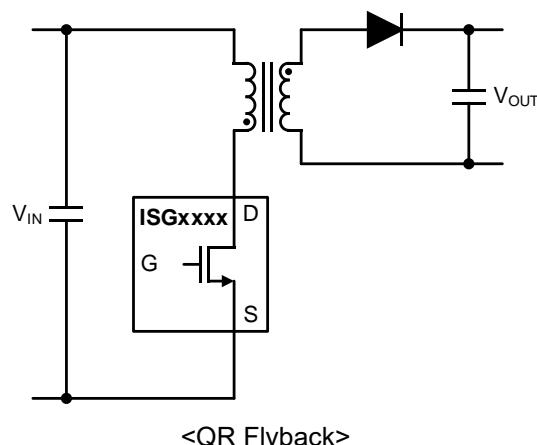
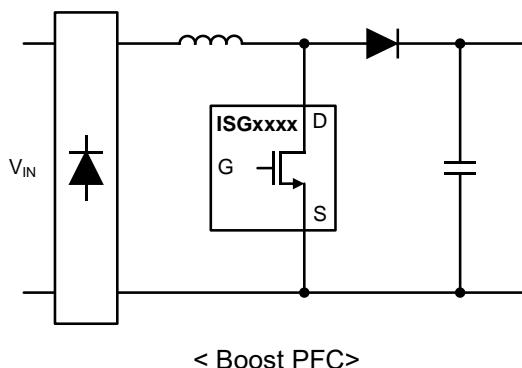


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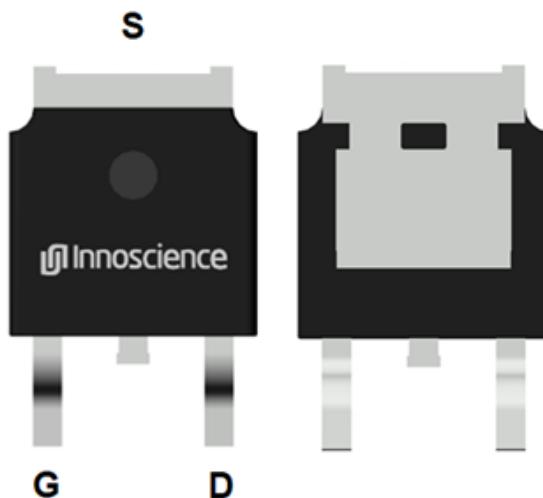
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5. Revision History

Major changes since the last revision

Revision	Date	Description of Changes
0.1	2025-02-14	Preliminary datasheet

6. Pin Configuration and Functions



3-Lead TO-252 Package

Pin Number	Pin Name	Description
1	G	Gate Input. Connect to the drive output of controller or gate driver.
2	S	Source of Power GaN FET.
3	D	Drain of Power GaN FET.

7. Absolute Maximum Ratings

All pins are referred to S pin, unless otherwise specified. Stress beyond the absolute maximum ratings can cause permanent damage or deteriorate device lifetime.

Parameter	Value	Unit
Drain Voltage, Continuous	700	V
Drain Voltage, Pulsed ⁽¹⁾	750	V
Drain Current, Continuous ($T_c = 25^\circ\text{C}$)	11.5	A
Drain Current, Pulsed (10us @ $T_c = 25^\circ\text{C}$)	20.5	A
Drain Current, Pulsed (10us @ $T_c = 125^\circ\text{C}$)	11.5	A
Gate Voltage, Continuous	-0.6 to 22	V
Gate Voltage, Pulsed ⁽¹⁾	-5 to 24	V
Power Dissipation	TBD	W
Operating Junction Temperature T_J	-40 to 150	°C
Storage Temperature	-55 to 150	°C

(1) Intended for repetitive events, $t_{\text{PULSE}} < 100\text{ns}$.

8. ESD Ratings

$T_J = 25^\circ\text{C}$ unless otherwise specified.

Parameter	Value	Unit
Human Body Model (HBM), per ANSI/ESDA/JEDEC JS-001	±2000	V
Charged Device Model (CDM), per ANSI/ESDA/JEDEC JS-002	±1000	V

9. Recommended Operating Conditions

Parameter	Min	Max	Unit
Gate Input High Voltage	8	20	V
Gate Input Low Voltage	-0.3	0.3	V
Operating Junction Temperature	-40	125	°C

10. Thermal Information

Symbol	Parameter	ISG6134ATK	Unit
R_{JA}	Thermal Resistance, Junction to Ambient	TBD	°C/W
R_{JC}	Thermal Resistance, Junction to Case	TBD	°C/W

According to standards defined in JESD51 and JESD51-1, thermal characteristics of the package are simulated. R_{JA} is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board.

11. Electrical Characteristics

$T_J = 25^\circ\text{C}$, $V_{GS} = 12\text{V}$, unless otherwise noted.

Parameter	Symbol	Min	Typ	Max	Unit	Test Condition
Gate Characteristic						
Gate input threshold voltage	V_{GS_TH}	3.6	4	4.4	V	
Gate quiescent current	I_{GON_Q}		200		uA	$V_{GS} = 12\text{V}$
Protection						
DESAT protection threshold ⁽²⁾	V_{DS_DESAT}		5.3		V	
DESAT blanking time ⁽²⁾	t_{BLK_DESAT}		600		ns	
Power GaN FET						
Drain-source leakage current	I_{DSs}		0.4 4	TBD	uA uA	$V_{GS}=0\text{V}$, $V_{DS}=700\text{V}$, $T_J=25^\circ\text{C}$ $V_{GS}=0\text{V}$, $V_{DS}=700\text{V}$, $T_J=150^\circ\text{C}$
Drain-source resistance	$R_{DS(ON)}$		160 378	210	mΩ	$V_{GS}=12\text{V}$, $I_{DS}=3\text{A}$; $T_J=25^\circ\text{C}$ $V_{GS}=12\text{V}$, $I_{DS}=3\text{A}$; $T_J=150^\circ\text{C}$
Source-drain reverse voltage	V_{SD}		2.4		V	$V_{GS}=0\text{V}$, $I_{SD}=3\text{A}$
Total gate charge ⁽²⁾	Q_G		1.71		nC	$V_{GS}=0\text{V}$, $V_{DS}=0$ to 400V
Output charge ⁽²⁾	Q_{OSS}		16.5		nC	$V_{GS}=0\text{V}$, $V_{DS}=0$ to 400V
Reverse recovery charge ⁽²⁾	Q_{RR}		0		nC	$V_{DS}=400\text{V}$, $I_{DS}=3\text{A}$
Input capacitance ⁽²⁾	C_{iss}		65		pF	$V_{GS}=0\text{V}$, $V_{DS}=400\text{V}$, $f=100\text{kHz}$
Output capacitance ⁽²⁾	C_{oss}		23.6		pF	$V_{GS}=0\text{V}$, $V_{DS}=400\text{V}$, $f=100\text{kHz}$
Effective output capacitance, energy related ⁽²⁾	$C_{O(er)}$		32		pF	$V_{GS}=0\text{V}$, $V_{DS}=0$ to 400V
Effective output capacitance, time related ⁽²⁾	$C_{O(tr)}$		42		pF	$V_{GS}=0\text{V}$, $V_{DS}=0$ to 400V

12. Switching Characteristics

$T_J = 25^\circ\text{C}$, $V_{GS} = 12\text{V}$, unless otherwise noted.

Parameter	Symbol	Min	Typ	Max	Unit	Test Condition
Turn-on propagation delay	t_{ON_PD}		100		ns	
Turn-off propagation delay	t_{OFF_PD}		100		ns	

(2) Not 100% tested and guaranteed by design.

13. Typical Characteristics

14. Block Diagram

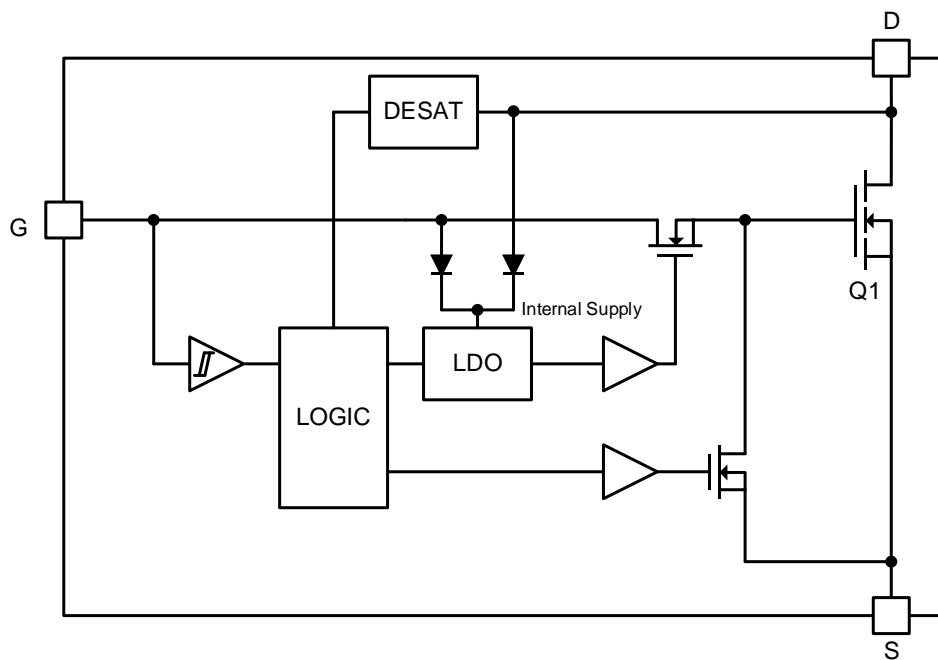


Figure 13. Functional Block Diagram

15. Function Description

The ISG6134A SolidGaN IC in a 3-lead TO-252 package contains high performance E-mode GaN FET with a built-in gate clamp and DESAT protection. It incorporates a self-powered feature without specified supply voltage for internal circuitry, converting supply either G or D pin corresponding its operation. This ensures consistent driving of GaN FET with easy-of-use and reliable operation.

The ISG6134A enables the independent adjustment of turn-on slew rate for driver by an external gate resistor, optimizing both EMI performance and efficiency. With the high integration level of GaN FET and robust protection, the ISG6134A offers a simple setup with a low component count, ensuring it is suitable for high-frequency and high-power applications.

Power-On-Sequence and Self-Powered Operation

The ISG6134A offers the self-powered feature without sustainable supply voltage for internal supply (VDD). It converts supply either G or D pin according to operation states to guarantee consistent driving of GaN FET.

Figure 14 shows the switching characteristics of the G and D. When the system is powered on, D pin is pulled high, the internal supply is powered from the D pin. The D voltage exceeding 30V is required for proper power supply typically. When G pin voltage goes above 4.0V, the internal GaN FET turns on with a time delay, t_{ON_PD} , and the D is pulled down to ground, powering the internal supply from G pin. When the G pin voltage goes below 4.0V, the internal GaN FET turns off with a time delay, t_{OFF_PD} .

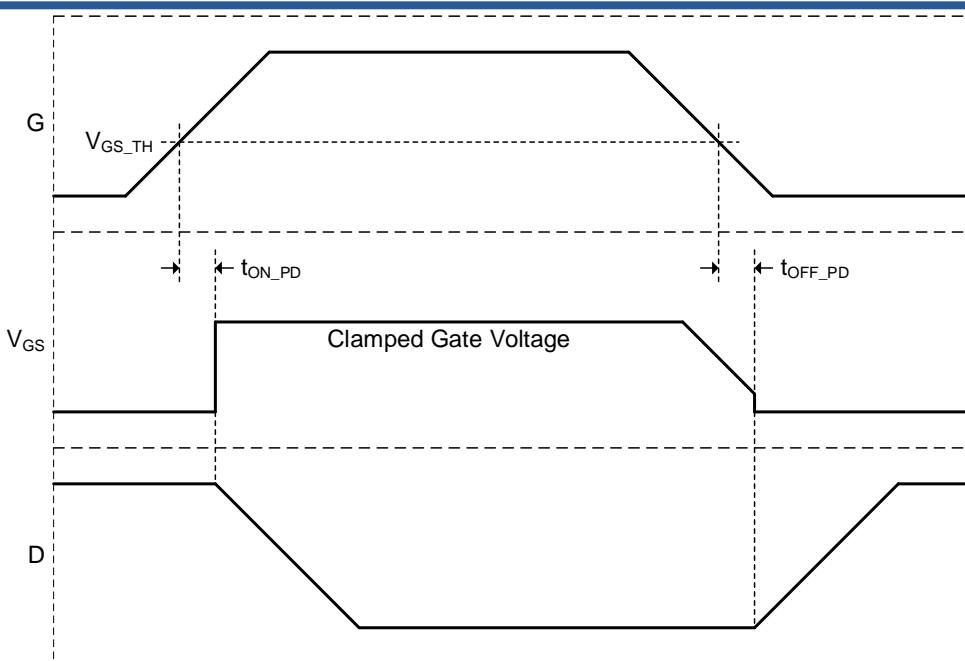


Figure 14. Timing Diagram of Input and Output

Adjustable Turn-On and Turn-Off Slew Rate

The ISG6134A supports users the ability to adjust both turn-on and turn-off slew rate of the GaN FET independently. This is achieved by adding external gate resistors and diode between the driver output and G pin of ISG6134A as shown in Figure 15, targeting optimization of efficiency, reliability, and EMI performance.

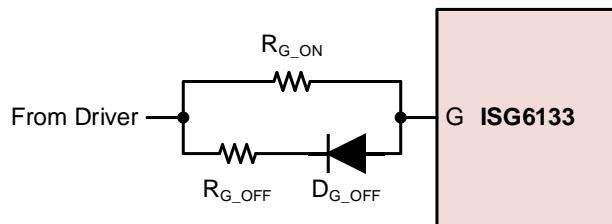


Figure 15. Configuration of Adjustable Turn-On Slew Rate

DESAT Protection

The ISG6134A provides cycle-by-cycle DESAT protection by monitoring the drain-source voltage, V_{DS}, to protect the GaN FET from potential damage in the desaturation region. As illustrated in the timing diagram of Figure 16, when the V_{DS} exceeds the DESAT protection threshold (5.9V typical), the GaN FET is turned off. The GaN FET will be turned on again at the next rising edge of G signal. The blanking time of 600ns (typical) is added to prevent false triggering during the GaN FET turn-on.

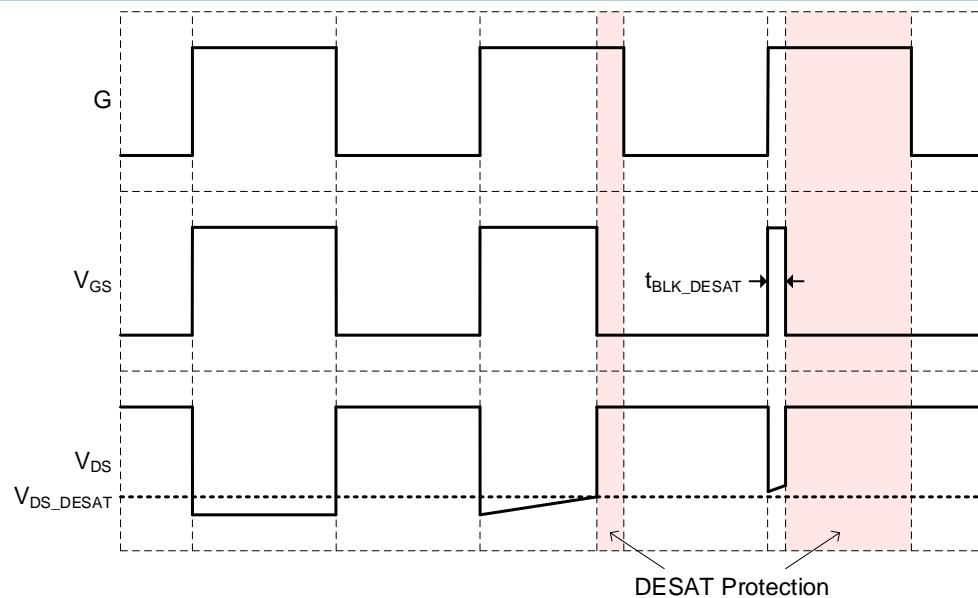
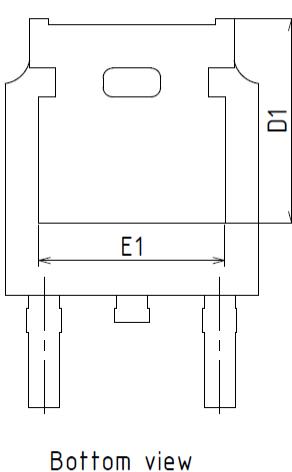
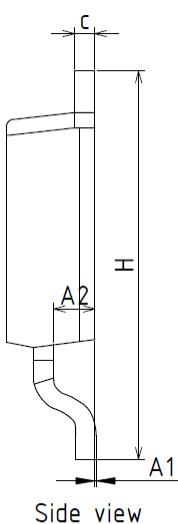
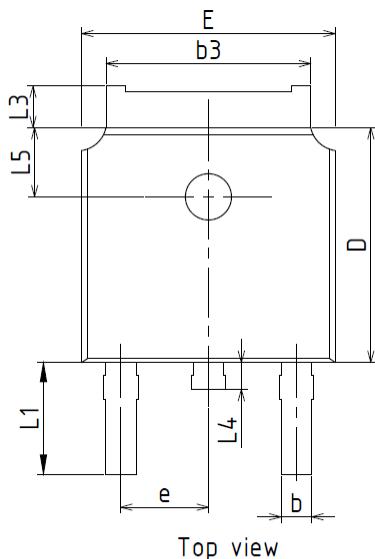
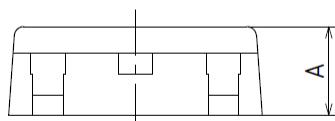


Figure 16. Timing Diagram of DESAT Protection

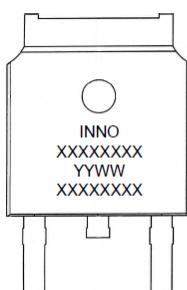
16. Package Information



SYMBOL	MILLIMETER		
	MIN	NOM	MAX
A	2.20	2.30	2.38
A1	0.00	-	0.12
A2	0.97	1.07	1.17
b	0.68	0.78	0.90
b3	5.20	5.33	5.46
c	0.43	0.53	0.61
D	5.98	6.10	6.22
D1	5.30REF		
E	6.40	6.60	6.73
E1	4.63	-	-
e	2.286BSC		
H	9.40	10.10	10.50
L	1.38	1.50	1.75
L1	2.90BSC		
L3	0.88	-	1.28
L4	0.50	-	1.00
L5	1.65	1.80	1.95

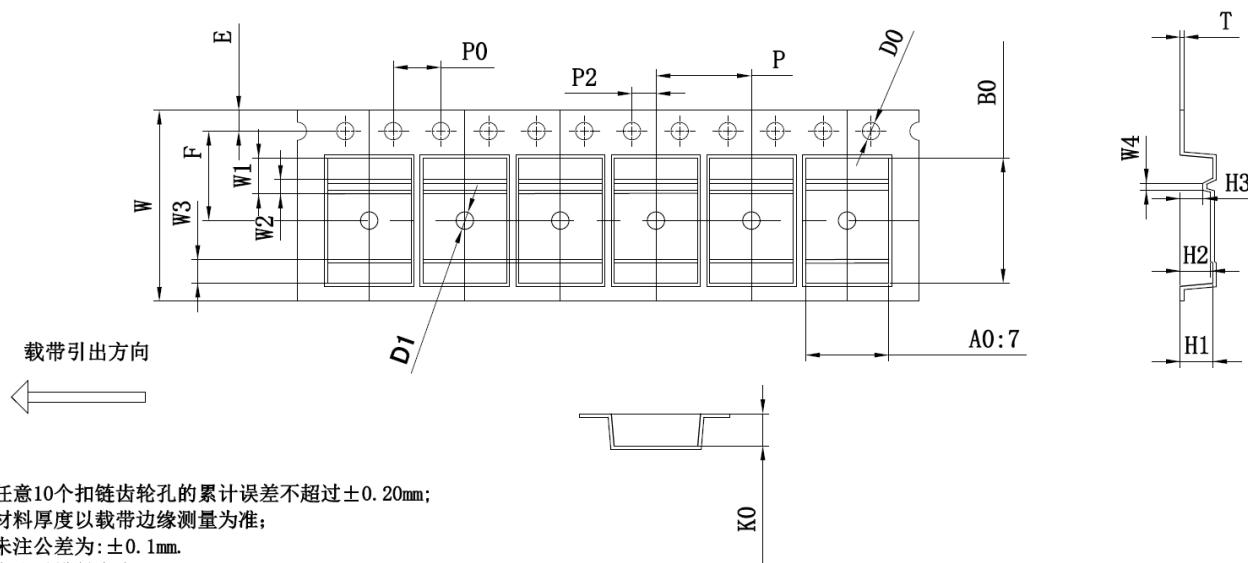


Side view



ROW	Description	Example
Row1	Company name	INNO
Row2	Product code	XXXXXXXXXX
Row3	Date code	YYWW
Row4	ASSY lot No.	XXXXXXXX

17. Tape and Reel Information



(1) 任意10个扣链齿轮孔的累计误差不超过 $\pm 0.20\text{mm}$;

(2) 材料厚度以载带边缘测量为准;

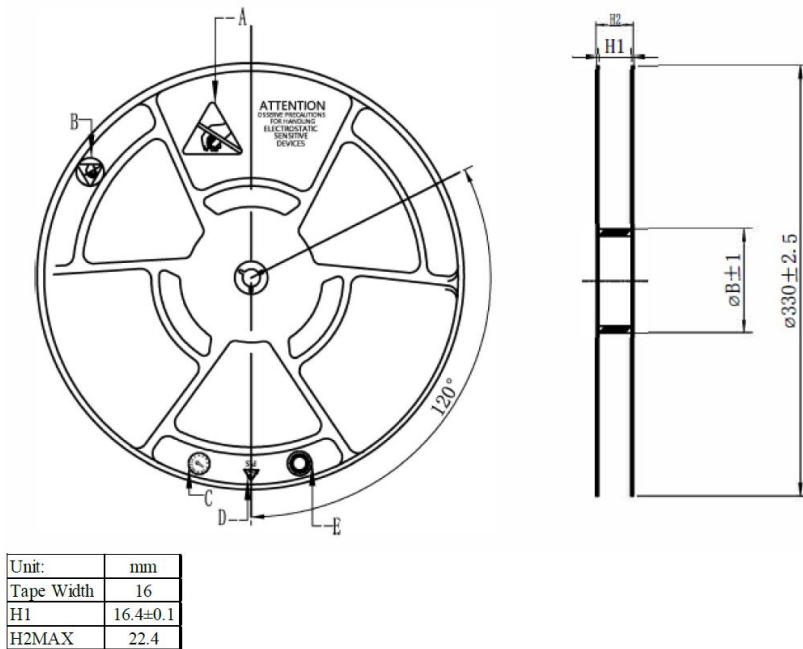
(3) 未注公差为: $\pm 0.1\text{mm}$.

(4) 未注脱模斜度为: 3° .

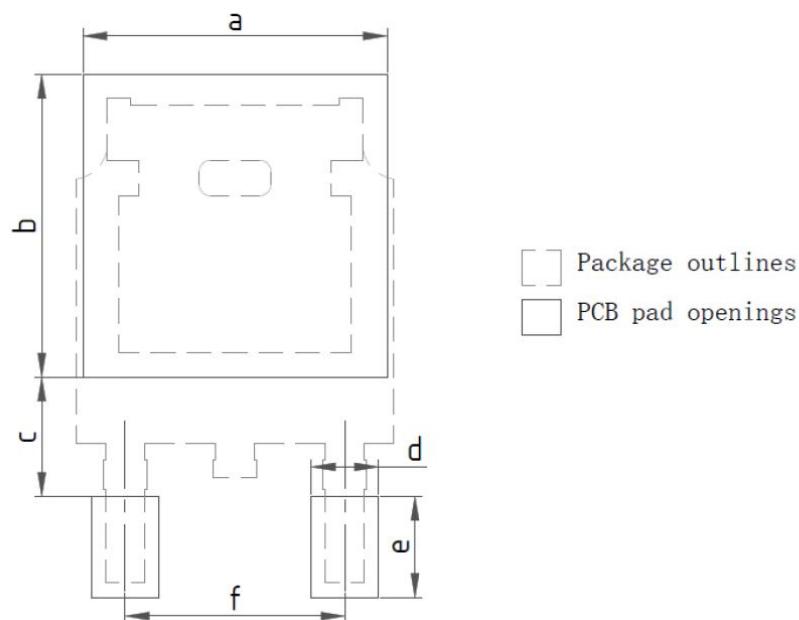
(5) 所有尺寸符合EIA-481-D版本.

(6) 材料: ABS-A0.

D	16.0	0.30	8.00	7.00	10.50	2.70	0.00	1.75	7.50	4.00	2.00	1.55	1.50	3.0	1.2	2.0	2.7	2.5	1.7	0.6
A	$+0.40$	$+0.05$	$+0.15$	$+0.20$	$+0.20$	$+0.15$	$+0.10$	$+0.15$	$+0.15$	$+0.15$	$+0.15$	$+0.15$	$+0.25$	$+0.15$	$+0.15$	$+0.15$	$+0.15$	$+0.15$	$+0.15$	$+0.15$
T	-0.20																			
A	W	T	P	A0	B0	K0	K1	E	F	P0	P2	D0	D1	W1	W2	W3	H1	H2	H3	W4



18. Recommended Land Pattern



SYMBOL	DIMENSION	SYMBOL	DIMENSION
a	6.33	d	1.40
b	6.30	e	2.10
c	2.48	f	4.57

Notes:

- (1) All dimension are in millimeters.
- (2) Drawing is not to scale.

19. Order Information

Ordering Code	Package	Product Code	MSL	Packing (Tape & Reel)
ISG6134ATK	TO-252-3L	6133ATK	MSL3	13" 2500PCS/reel

Important Notice

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